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Patent Search

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Abstract:

[025] The present invention discloses an Artificial Intelligence and IoT based fabric defect detection system and method thereof. In the present invention, an Artificial based apparatus for generating ultrasonic waves relative to the fabric, the IoT apparatus containing a number of ultrasonic transducers; reception apparatus for rece ultrasonic waves coupled through the fabric and generating a signal in response to IoT apparatus. Further, the data acquisition means coupled to the synchronizer m disposed to synchronise data acquisition with the fabric's travel on the loom and the travel of the fabric on the loom Synchronizer means for synchronising the journ fabric and the acquisition of image data. Accompanied Drawing [FIGS. 1-2]

Complete Specification

Description:[001] The present invention relates to the field of the AI-powered advanced fabric defect detection system with novel techniques, methods, devices and apparatus. The invention more particularly relates to an Artificial Intelligence and IoT based fabric defect detection system and method thereof.

BACKGROUND OF THE INVENTION

[002] The following description provides the information that may be useful in understanding the present invention. It is not an admission that any of the informati provided herein is prior art or relevant to the presently claimed invention, or that any publication specifically or implicitly referenced is prior art.

[003] Further, the approaches described in this section are approaches that could be pursued, but not necessarily approaches that have been previously conceived pursued. Therefore, unless otherwise indicated, it should not be assumed that any of the approaches described in this section qualify as prior art merely by virtue c inclusion in this section.

[004] Woven fabric quality is determined by the quantity of manufacturing flaws that remain after weaving. The steps of shedding, picking, and battening are repeat certain order to complete a weave. A loom performs all of these operations automatically. In order to pass a filler yarn through, the shed must be created by raising lowering the warp yarns. To pick means to enter a filler yarn through the shed so that it crosses over the warp threads. When a new fabric is woven, the filler yarn is battened by pressing it against the fall.

[005] Accordingly, on the basis of aforesaid facts, there remains a need in the prior art to provide an Artificial Intelligence and IoT based fabric defect detection syste method thereof. Therefore, it would be useful and desirable to have a system, method, apparatus and interfaces to meet the above-mentioned needs.

SUMMARY OF THE PRESENT INVENTION

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